Data Sheet

January 2002

50A, 60V, 0.022 Ohm, N-Channel Power MOSFETs

These N-Channel power MOSFETs are manufactured using the MegaFET process. This process, which uses feature sizes approaching those of LSI integrated circuits gives optimum utilization of silicon, resulting in outstanding performance. They were designed for use in applications such as switching regulators, switching converters, motor drivers, and relay drivers. These transistors can be operated directly from integrated circuits.

Formerly developmental type TA49018.

Ordering Information

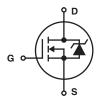
PART NUMBER	PACKAGE	BRAND
RFG50N06	TO-247	RFG50N06
RFP50N06	TO-220AB	RFP50N06
RF1S50N06SM	TO-263AB	F1S50N06

NOTE: When ordering, use the entire part number. Add the suffix, 9A, to obtain the TO-263AB variant in tape and reel, i.e. RF1S50N06SM9A.

Features

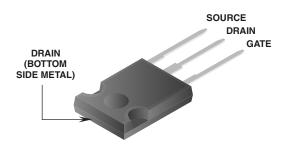
- 50A, 60V
- $r_{DS(ON)} = 0.022\Omega$
- Temperature Compensating PSPICE® Model
- Peak Current vs Pulse Width Curve
- UIS Rating Curve
- 175°C Operating Temperature

Symbol

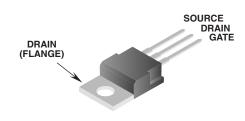


Packaging

JEDEC STYLE TO-247



JEDEC TO-220AB



JEDEC TO-263AB



RFG50N06, RFP50N06, RF1S50N06SM

Absolute Maximum Ratings $T_C = 25^{\circ}C$, Unless Otherwise Specified

	RFG50N06, RFP50N06		
	RF1S50N06SM	UNITS	
Drain to Source Voltage (Note 1)	60	V	
Drain to Gate Voltage ($R_{GS} = 20k\Omega$) (Note 1) V_{DGR}	60	V	
Gate to Source Voltage	±20	V	
Continuous Drain Current (Figure 2)	50 (Figure 5)	Α	
Pulsed Avalanche RatingE _{AS}	(Figure 6)		
Power Dissipation	131 0.877	W/°C	
Operating and Storage Temperature	-55 to 175	°C	
Maximum Temperature for Soldering Leads at 0.063in (1.6mm) from Case for 10s	300	°C	
Package Body for 10s, see Techbrief 334	260	°C	

CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

NOTE:

1. $T_J = 25^{\circ}C$ to $150^{\circ}C$.

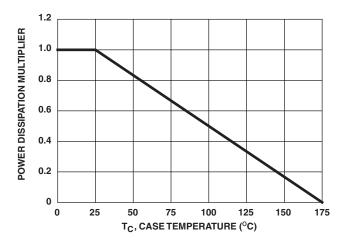
$\textbf{Electrical Specifications} \hspace{0.5cm} \textbf{T}_{C} = 25^{o}\text{C, Unless Otherwise Specified}$

PARAMETER	SYMBOL	TEST CONDITIONS		MIN	TYP	MAX	UNITS
Drain to Source Breakdown Voltage	BV _{DSS}	I _D = 250μA, V _{GS} = 0V (Figure 11)		60	-	-	V
Gate to Source Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}, I_{D} = 250\mu A \text{ (Figure 10)}$		2	-	4	V
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 60V,	$T_{C} = 25^{\circ}C$	-	-	1	μΑ
		$V_{GS} = 0V$ $T_C = 150^{\circ}C$	-	-	50	μА	
Gate to Source Leakage Current	I _{GSS}	V _{GS} = ±20V	V _{GS} = ±20V		-	±100	nA
Drain to Source On Resistance	r _{DS(ON)}	I _D = 50A, V _{GS} =	I _D = 50A, V _{GS} = 10V (Figures 9)		-	0.022	Ω
Turn-On Time	t _{ON}	$V_{DD} = 30V, I_{D} = 50A$ $R_{L} = 0.6\Omega, V_{GS} = 10V$ $R_{GS} = 3.6\Omega$ (Figure 13)		-	-	95	ns
Turn-On Delay Time	t _{d(ON)}			-	12	-	ns
Rise Time	t _r			-	55	-	ns
Turn-Off Delay Time	t _{d(OFF)}		-	37	-	ns	
Fall Time	t _f		-	13	-	ns	
Turn-Off Time	tOFF	1		-	-	75	ns
Total Gate Charge	Q _{g(TOT)}	V _{GS} = 0 to 20V	$V_{DD} = 48V, I_D = 50A,$	-	125	150	nC
Gate Charge at 10V	Q _{g(10)}	$V_{GS} = 0 \text{ to } 10V$ $R_{L} = 0.96\Omega$ $I_{g(REF)} = 1.45\text{mA}$ (Figure 13)		-	67	80	nC
Threshold Gate Charge	Q _{g(TH)}			-	3.7	4.5	nC
Input Capacitance	C _{ISS}	V _{DS} = 25V, V _{GS} = 0V f = 1MHz (Figure 12)		-	2020	-	pF
Output Capacitance	C _{OSS}			-	600	-	pF
Reverse Transfer Capacitance	C _{RSS}			-	200	-	pF
Thermal Resistance Junction to Case	$R_{ heta JC}$	(Figure 3)		-	-	1.14	°C/W
Thermal Resistance Junction to Ambient	$R_{\theta JA}$	TO-247 TO-220, TO-263		-	-	30	°C/W
				-	-	62	°C/W

Source to Drain Diode Specifications

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNITS
Source to Drain Diode Voltage	V _{SD}	I _{SD} = 50A	-	-	1.5	V
Reverse Recovery Time	t _{rr}	$I_{SD} = 50A$, $dI_{SD}/dt = 100A/\mu s$		-	125	ns

Typical Performance Curves Unless Otherwise Specified



60 50 50 40 30 20 20 25 50 75 100 125 150 175 T_C, CASE TEMPERATURE (°CC)

FIGURE 1. NORMALIZED POWER DISSIPATION vs CASE TEMPERATURE

FIGURE 2. MAXIMUM CONTINUOUS DRAIN CURRENT vs CASE TEMPERATURE

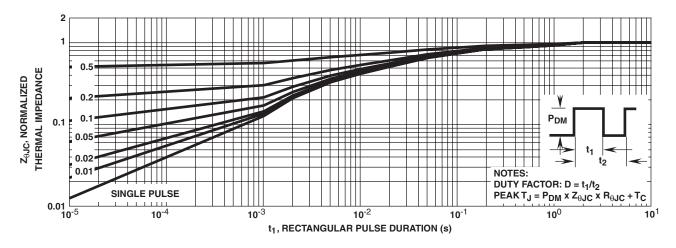


FIGURE 3. NORMALIZED MAXIMUM TRANSIENT THERMAL IMPEDANCE

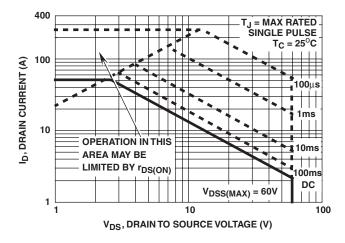


FIGURE 4. FORWARD BIAS SAFE OPERATING AREA

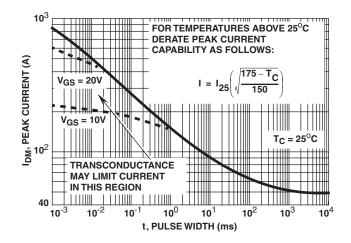
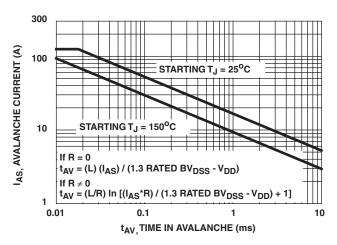


FIGURE 5. PEAK CURRENT CAPABILITY

Typical Performance Curves Unless Otherwise Specified (Continued)



NOTE: Refer to Fairchild Application Notes 9321 and 9322.

FIGURE 6. UNCLAMPED INDUCTIVE SWITCHING CAPABILITY

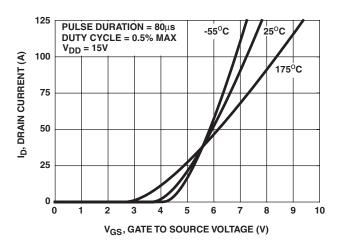


FIGURE 8. TRANSFER CHARACTERISTICS

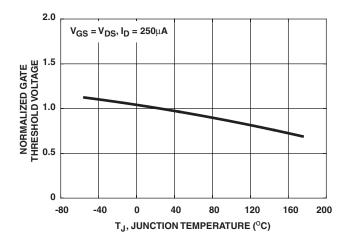


FIGURE 10. NORMALIZED GATE THRESHOLD VOLTAGE vs JUNCTION TEMPERATURE

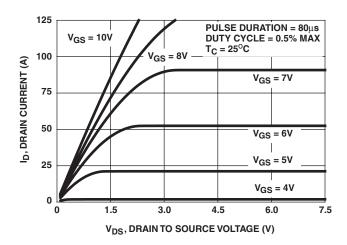


FIGURE 7. SATURATION CHARACTERISTICS

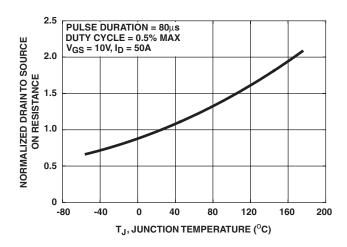


FIGURE 9. NORMALIZED DRAIN TO SOURCE ON RESISTANCE vs JUNCTION TEMPERATURE

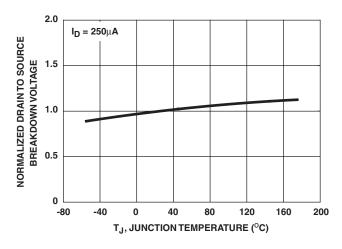


FIGURE 11. NORMALIZED DRAIN TO SOURCE BREAKDOWN VOLTAGE vs JUNCTION TEMPERATURE

Typical Performance Curves Unless Otherwise Specified (Continued)

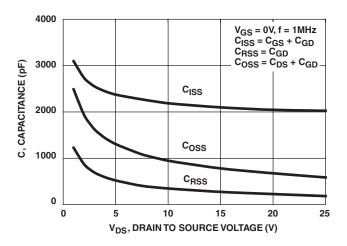


FIGURE 12. CAPACITANCE vs DRAIN TO SOURCE VOLTAGE

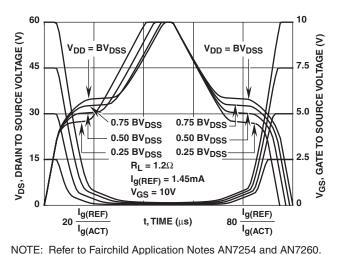


FIGURE 13. NORMALIZED SWITCHING WAVEFORMS FOR
CONSTANT GATE CURRENT

Test Circuits and Waveforms

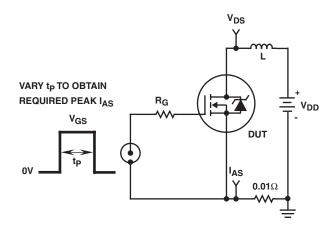


FIGURE 14. UNCLAMPED ENERGY TEST CIRCUIT

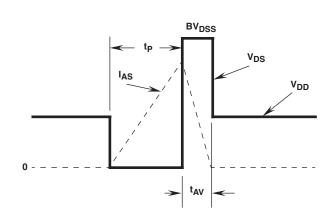


FIGURE 15. UNCLAMPED ENERGY WAVEFORMS

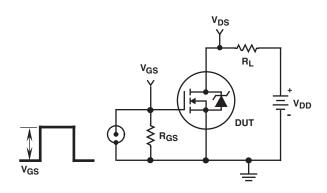


FIGURE 16. SWITCHING TIME TEST CIRCUIT

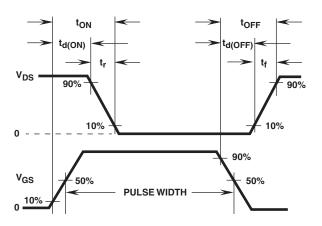


FIGURE 17. SWITCHING WAVEFORMS

Test Circuits and Waveforms (Continued)

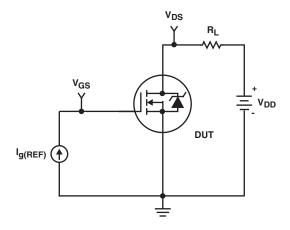


FIGURE 18. GATE CHARGE TEST CIRCUIT

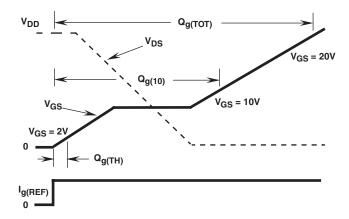


FIGURE 19. GATE CHARGE WAVEFORMS

PSPICE Electrical Model

SUBCKT RFP50N06 2 1 3

REV 2/22/93

*NOM TEMP = 25°C

CA 12 8 3.68e-9 CB 15 14 3.625e-9 CIN 6 8 1.98e-9

DBODY 7 5 DBDMOD DBREAK 5 11DBKMOD DPLCAP 10 5 DPLCAPMOD

EBREAK 11 7 17 18 64.59 EDS 14 8 5 8 1 EGS 13 8 6 8 1 ESG 6 10 6 8 1 EVTO 20 6 18 8 1

IT 8 17 1

LDRAIN 2 5 1e-9 LGATE 1 9 5.65e-9 LSOURCE 3 7 4.13e-9

MOS1 16 6 8 8 MOSMOD M=0.99 MOS2 16 21 8 8 MOSMOD M=0.01

RBREAK 17 18 RBKMOD 1 RDRAIN 5 16 RDSMOD 1e-4 RGATE 9 20 0.690 RIN 6 8 1e9 RSOURCE 8 7 RDSMOD 12e-3 RVTO 18 19 RVTOMOD 1

S1A 6 12 13 8 S1AMOD S1B 13 12 13 8 S1BMOD S2A 6 15 14 13 S2AMOD S2B 13 15 14 13 S2BMOD

VBAT 8 19 DC 1 VTO 21 6 0.678

DRAIN 5 10 LDRAIN **DPLCAP RDRAIN** DBREAK **ESG** 16 VTO **DBODY** MOS2 **EVTO GATE** 21 $\frac{18}{8}$ i∢ MOS1 LGATE **RGATE** EBREAK (RIN CIN RSOURCE **LSOURCE** 8 **—**0 3 S1A S2A SOURCE RBREAK 13 14 13 15 17 18 8 Q S2B S1B ₹ RVTO 13 СВ CA lacktriangleIT 19 **VBAT EGS EDS**

.MODEL DBDMOD D (IS=9.85e-13 RS=4.91e-3 TRS1=2.07e-3 TRS2=2.51e-7 CJO=2.05e-9 TT=4.33e-8)

.MODEL DBKMOD D (RS=1.98e-1 TRS1=2.35E-4 TRS2=-3.83e-6)

.MODEL DPLCAPMOD D (CJO=1.42e-9 IS=1e-30 N=10)

.MODEL MOSMOD NMOS (VTO=3.65 KP=35 IS=1e-30 N=10 TOX=1 L=1u W=1u)

.MODEL RBKMOD RES (TC1=1.23e-3 TC2=-2.34e-7)

.MODEL RDSMOD RES (TC1=5.01e-3 TC2=1.49e-5)

.MODEL RVTOMOD RES (TC1=-5.03e-3 TC2=-5.16e-6)

.MODEL S1AMOD VSWITCH (RON=1e-5 ROFF=0.1 VON=-6.75 VOFF=-2.5)

.MODEL S1BMOD VSWITCH (RON=1e-5 ROFF=0.1 VON=-2.5 VOFF=-6.75)

.MODEL S2AMOD VSWITCH (RON=1e-5 ROFF=0.1 VON=-2.7 VOFF=2.3)

.MODEL S2BMOD VSWITCH (RON=1e-5 ROFF=0.1 VON=2.3 VOFF=-2.7)

.ENDS

NOTE: For further discussion of the PSPICE model consult **A New PSPICE Sub-Circuit for the Power MOSFET Featuring Global Temperature Options;** authors, William J. Hepp and C. Frank Wheatley.

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